MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data sheet



Semiconductor

Compiance

The ESD9L is designed to protect voltage sensitive components that require ultra-low capacitance from ESD and transient voltage events. Excellent clamping capability, low capacitance, low leakage, and fast response time, make these parts ideal for ESD protection on designs where board space is at a premium. Because of its low capacitance, it is suited for use in high frequency designs such as USB 2.0 high speed and antenna line applications.

Specification Features:

- Ultra Low Capacitance 0.5 pF
- Low Clamping Voltage
- Small Body Outline Dimensions: 0.039" x 0.024" (1.00 mm x 0.60 mm)
- Low Body Height: 0.016" (0.4 mm)
- Stand-off Voltage: 5 V
- Low Leakage
- Response Time is Typically < 1.0 ns
- IEC61000-4-2 Level 4 ESD Protection
- This is a Pb-Free Device

Mechanical Characteristics:

CASE: Void-free, transfer-molded, thermosetting plastic

Epoxy Meets UL 94 V-0

LEAD FINISH: 100% Matte Sn (Tin)

MOUNTING POSITION: Any

QUALIFIED MAX REFLOW TEMPERATURE: $260^{\circ}\mathrm{C}$

Device Meets MSL 1 Requirements

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
IEC 61000-4-2 (ESD) Contact		±10	kV
Total Power Dissipation on FR-5 Board (Note 1) @ T _A = 25°C	P _D	150	mW
Storage Temperature Range	T _{stg}	-55 to +150	°C
Junction Temperature Range	T_J	-55 to +125	°C
Lead Solder Temperature - Maximum (10 Second Duration)	TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. $FR-5 = 1.0 \times 0.75 \times 0.62$ in.



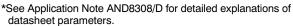


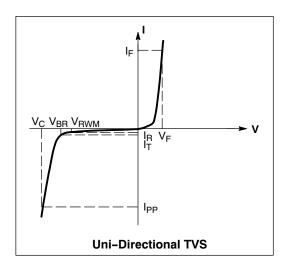
SOD-923

ELECTRICAL CHARACTERISTICS

(T_A = 25°C unless otherwise noted)

Symbol	Parameter			
I _{PP}	Maximum Reverse Peak Pulse Current			
V _C	Clamping Voltage @ I _{PP}			
V _{RWM}	Working Peak Reverse Voltage			
I _R	Maximum Reverse Leakage Current @ V _{RWM}			
V_{BR}	Breakdown Voltage @ I _T			
Ι _Τ	Test Current			
lF	Forward Current			
V _F	Forward Voltage @ I _F			
P _{pk}	Peak Power Dissipation			
С	Max. Capacitance @ V _R = 0 and f = 1.0 MHz			





ELECTRICAL CHARACTERISTICS ($T_A = 25^{\circ}C$ unless otherwise noted, $V_F = 1.0 \text{ V Max.}$ @ $I_F = 10 \text{ mA}$ for all types)

		V _{RWM} (V)	I _R (μΑ) @ V _{RWM}	V _{BR} (V) @ I _T (Note 2)	I _T	C (pF)	v _c
Device	Device Marking	Max	Max	Min	mA	Тур	Max	Per IEC61000-4-2 (Note 3)
ESD9L5.0ST5G	D	5.0	1.0	5.8	1.0	0.5	0.9	Figures 1 and 2 See Below

- 2. V_{BR} is measured with a pulse test current I_T at an ambient temperature of 25°C.
- 3. For test procedure see Figures 3 and 4 and Application Note AND8307/D.

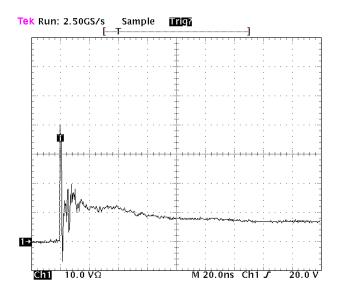


Figure 1. ESD Clamping Voltage Screenshot Positive 8 kV Contact per IEC61000-4-2

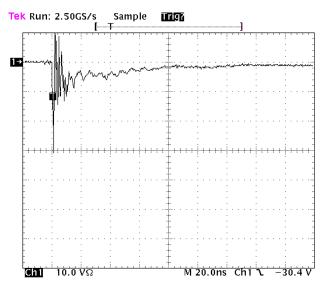
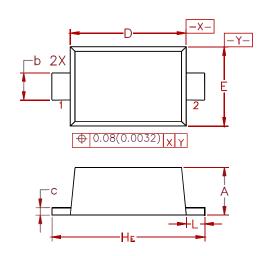


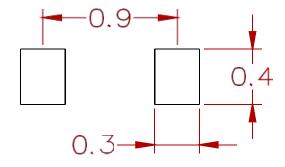
Figure 2. ESD Clamping Voltage Screenshot Negative 8 kV Contact per IEC61000-4-2

PACKAGE MECHANICAL DATA



		Millimeters		Inches			
Dim	Min	Nom	Max	Min	Nom	Max	
Α	0.36	0.40	0.43	0.014	0.016	0.017	
b	0.15	0.20	0.25	0.006	0.008	0.010	
С	0.07	0.12	0.17	0.003	0.005	0.007	
D	0.75	0.80	0.85	0.030	0.031	0.033	
E	0.55	0.60	0.65	0.022	0.024	0.026	
HE	0.95	1.00	1.05	0.037	0.039	0.041	
L	0.05	0.10	0.15	0.002	0.004	0.006	

Suggested Pad Layout



Dimensions: Millimeters

REEL SPECIFICATION

P/N	PKG	QTY
MSESD9L5.0ST09	SOD-923	8000



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